| | | Application/Control No. | Applicant(s)/Patent Under Reexamination |
|---|---|---|---|
| **Notice of References Cited** | | 10/068,307 | FIRTH ET AL. |
| | | Examiner | Art Unit | |
| | | Cynthia Britt | 2133 | Page 1 of 1 |

## U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|---|---|---|---|
| | A | US-5,488,612 A | 01-1996 | Heybruck, William F. | 714/725 |
| | B | US-6,242,269 B1 | 06-2001 | Whetsel, Lee D. | 438/11 |
| | C | US-6,353,563 B1 | 03-2002 | Hii et al. | 365/201 |
| | D | US-6,622,269 B1 | 09-2003 | Ngo et al. | 714/718 |
| | E | US-6,768,292 B2 | 07-2004 | Hapke, Friedrich | 324/73.1 |
| | F | US-4,546,472 A | 10-1985 | Volk et al. | 714/724 |
| | G | US-4,903,266 A | 02-1990 | Hack, George E. | 714/719 |
| | H | US-5,488,612 A | 01-1996 | Heybruck, William F. | 714/725 |
| | I | US-5,883,843 A | 03-1999 | Hii et al. | 365/201 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

## FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|---|---|---|---|---|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

## NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | "A Tutorial on Built-in Self-test. (part 2 Applications)" Agrawal et al. IEEE Design & Test of Computers, Publication Date: June 1993 pages 69 - 77 Vol:10, Issue:2 ISSN: 0740-7475  Inspec Accession Number: 4464928 |
| | V | "A Programmable Built-in Self-test Core for Embedded Memories" Huang  et al. Proceedings of the ASP-DAC Design Automation Conference, 2000. Publication Date: 25-28 Jan. 2000 pages11-12 Inspec Accession Number: 6596958 |
| | W | "An ASIC Library Granular DRAM Macro with Built-in Self-test" Dreibelbis et al. Solid-State Circuits Conference, Digest of Technical Papers Publication Date: 5-7 Feb. 1998 pages74-75, 416 Inspec Accession Number: 5979214 |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office
PTO-892 (Rev. 01-2001)                    **Notice of References Cited**                    Part of Paper No. 20040831